

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

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ATTY. DOCKET NO.
M122-1943

SERIAL NO.
Priority 09/146,838

APPLICANT
David L. Dickerson et al.

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GROUP
2814

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
A.M	AA 5,674,775	10/7/97	Ho et al.			
	AB 6,040,232	3/21/00	Gau	438	424	
	AC 6,074,932	6/13/00	Wu	438	424	
	AD 6,090,684	7/18/00	Ishitsuka et al.	438	424	
	AE 6,093,621	7/25/00	Tseng	438	424	
	AF 6,103,635	8/15/00	Chau et al.	438	424	
	AG 6,153,480	11/28/00	Arghavani et al.	438	424	
	AH 5,981,356	11/99	Hsueh et al.	438	424	
	AI 5,989,975	11/99	Kuo	438	424	
	AJ 6,153,478	11/00	Lin et al.	438	424	
	AK 6,232,203 B1	05/01	Huang	438	296	
	AL 6,249,035 B1	06/01	Peidous et al.	438	424	
				257	506	

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Document Number	Date	Country	Class	Subclass	Translation
A.M AM EP 0 782 185 A2	02.07.97	Europe (NEC Corporation)			Yes No
AN EP 0 782 185 A3	02.08.97	Europe (NEC Corporation)			
AO JP 11-67890		Japan			
AP					
AQ					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

A.M	AR	IBM Corp., Optimized Shallow Trench Isolation Structure and Its Process for Eliminating Shallow Trench Isolation-Induced Parasitic Effects,
		34 IBM Technical Disclosure Bulletin, No. 11, pp. 276-277 (April 1992).
A.M	AS	Texas Instruments SPIE, Vol. 2875, A Study of Integration Issues in Shallow Trench Isolation for Deep Submicron CMOS Technologies
		pgs. 39-43 Chatterje, Mason, Joyner, Rogers, Mercer, Kuehne, Esquivel, Mei, Murtaza, Taylor, Ali, Nag, O'Brien, Ashburn and Chen
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J1046 U.S. PTO

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Form PTO-1449

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
A.M	AA 4,663,832	05/12/87	Jambotkar			
	AB 5,677,233	10/14/97	Abiko	438	437	
	AC 5,712,185	01/27/98	Tsai et al.	438	424	
	AD 5,780,346	07/14/98	Arghavani et al.	438	424	
	AE 5,801,083	09/01/98	Yu et al.	438	296	
	AF 5,895,254	04/20/99	Huang et al.	438	424	
	AG 5,397,733	3/14/95	Jang	438	424	
	AH 5,728,620	3/17/98	Park	438	439	
	AI 5,904,538	05/18/99	Son et al.	438	425	
	AJ 5,966,614	10/12/99	Park et al.	438	424	
	AK 6,083,808	7/4/00	Shin et al.	438	424	
	AL 5,863,827	01/26/99	Joyner	438	424	
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A.M	AA 5,933,749	08/03/99	Lee			
	AB 5,937,308	08/10/99	Gardner et al.	438	435	
	AC 5,960,297	09/28/99	Saki	438	424	
	AD 5,356,828	10/18/94	Swan et al.	438	424	
	AE 5,976,948	11/02/99	Werner et al.	437 438	427	
	AF 5,962,342	10/05/99	Chuang et al.	438	424	
	AG 6,177,331 B1	01/23/01	Koga	438	692	
	AH 4,533,430	08/06/85	Bower	438	424	
	AI 4,882,291	11/21/89	Jeuch	438 438	424	
	AJ 5,258,332	11/02/93	Horioka et al.	438 438	424	
	AK 5,506,168	04/09/96	Morita et al.	438 438	424	
	AL 5,554,256	09/10/96	Pruijboom et al.	438 438	424	

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A. M	AA	5,578,518	11/26/96	Koike et al.	438	424	
	AB	5,834,358	11/10/98	Pan et al.	438	424	
	AC	5,880,004	03/09/99	Ho	438	421	
	AD	6,245,640	06/12/01	Claussen et al.	438	424	
	AE	6,284,623 B1	09/04/01	Zhang et al.	438	424	
	AF	6,284,625 B1	09/04/01	Ishitsuka et al.	438	425	
	AG	6,287,921 B1	09/11/01	Chern	438	289	
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	AJ						
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	AL						

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